


<b>Search Notes</b>  	<b>Application/Control No.</b>  10586682	<b>Applicant(s)/Patent Under Reexamination</b>  LEYRER ET AL.
	<b>Examiner</b>  HUI CHIN	<b>Art Unit</b>  4131

SEARCHED			
Class	Subclass	Date	Examiner
524	543	10/9/2008	HC
524	800	10/9/2008	HC
524	459	10/9/2008	HC
568	792	10/9/2008	HC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search	10/9/2008	HC
Inventor search on eDAN	10/9/2008	HC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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